

Complementary MOSFET

ELM24604HA-S

General Description

ELM24604HA-S uses advanced trench technology to provide excellent $R_{ds(on)}$ and low gate charge.

Features

N-channel	P-channel
$V_{ds}=40V$	$V_{ds}=-40V$
$I_d=8A(V_{gs}=10V)$	$I_d=-8A(V_{gs}=-10V)$
$R_{ds(on)} < 33m\Omega (V_{gs}=10V)$	$R_{ds(on)} < 50m\Omega (V_{gs}=-10V)$
$R_{ds(on)} < 47m\Omega (V_{gs}=4.5V)$	$R_{ds(on)} < 70m\Omega (V_{gs}=-4.5V)$

Maximum Absolute Ratings

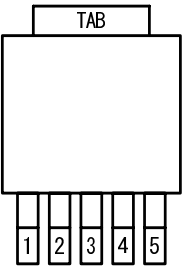
Parameter		Symbol	N-ch (Max.)	P-ch (Max.)	Unit	Note
Drain-source voltage		V_{ds}	40	-40	V	
Gate-source voltage		V_{gs}	± 20	± 20	V	
Continuous drain current	$T_c=25^{\circ}C$	I_d	8	-8	A	7
	$T_c=100^{\circ}C$		8	-8		
Pulsed drain current		I_{dm}	30	-30	A	3
Avalanche current		I_{ar}	8	-8	A	3
Repetitive avalanche energy $L=0.1mH$		E_{ar}	20	30	mJ	3
Power dissipation	$T_c=25^{\circ}C$	P_d	20	50	W	2
	$T_c=100^{\circ}C$		10	25		
Power dissipation	$T_a=25^{\circ}C$	P_{dsm}	2.0	2.5	W	1
	$T_a=70^{\circ}C$		1.3	1.6		
Junction and storage temperature range		T_j, T_{stg}	-55 to 150	-55 to 150	$^{\circ}C$	

Thermal Characteristics

Parameter		Symbol	Device	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$t \leq 10s$	$R\theta_{ja}$	N-ch	17.4	30.0	$^{\circ}C/W$	1
Maximum junction-to-ambient	Steady-state			50.0	60.0	$^{\circ}C/W$	
Maximum junction-to-case	Steady-state	$R\theta_{jc}$		4.0	7.5	$^{\circ}C/W$	2
Maximum junction-to-ambient	$t \leq 10s$	$R\theta_{ja}$	P-ch	16.7	25.0	$^{\circ}C/W$	1
Maximum junction-to-ambient	Steady-state			40.0	50.0	$^{\circ}C/W$	
Maximum junction-to-case	Steady-state	$R\theta_{jc}$		2.5	3.0	$^{\circ}C/W$	2

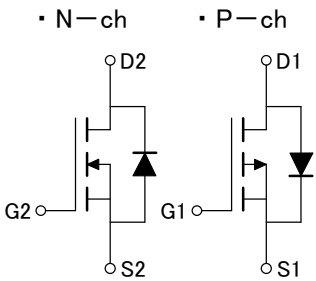
Pin Configuration

TO-252-5 (TOP VIEW)



Pin No.	Pin name
1	SOURCE1
2	GATE1
3	DRAIN1/DRAIN2
4	GATE2
5	SOURCE2

Circuit



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■ Electrical Characteristics (N-ch)

T_a=25°C

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
STATIC PARAMETERS						
Drain-source breakdown voltage	BV _{dss}	I _d =10mA, V _{gs} =0V	40			V
Zero gate voltage drain current	I _{dss}	V _d =32V V _{gs} =0V			1	μA
		T _j =55°C			5	
Gate-body leakage current	I _{gss}	V _d =0V, V _{gs} =±20V			100	nA
Gate threshold voltage	V _{gs(th)}	V _d =V _{gs} , I _d =250 μA	1.0	2.3	3.0	V
On state drain current	I _{d(on)}	V _{gs} =10V, V _d =5V	30			A
Static drain-source on-resistance	R _{ds(on)}	V _{gs} =10V I _d =8A		25	33	mΩ
		T _j =125°C		39	52	
		V _{gs} =4.5V, I _d =6A		34	47	
Forward transconductance	G _{fs}	V _d =5V, I _d =8A		25		S
Diode forward voltage	V _{sd}	I _s =1A, V _{gs} =0V		0.76	1.00	V
Max.body-diode continuous current	I _s				8	A
DYNAMIC PARAMETERS						
Input capacitance	C _{iss}	V _{gs} =0V, V _d =20V, f=1MHz		404		pF
Output capacitance	C _{oss}			95		pF
Reverse transfer capacitance	C _{rss}			37		pF
Gate resistance	R _g	V _{gs} =0V, V _d =0V, f=1MHz		2.7		Ω
SWITCHING PARAMETERS						
Total gate charge (10V)	Q _g	V _{gs} =10V, V _d =20V, I _d =8A		9.2		nC
Total gate charge (4.5V)	Q _g			4.5		nC
Gate-source charge	Q _{gs}			1.6		nC
Gate-drain charge	Q _{gd}			2.6		nC
Turn-on delay time	t _{d(on)}			3.5		ns
Turn-on rise time	t _r	V _{gs} =10V, V _d =20V		6.0		ns
Turn-off delay time	t _{d(off)}	R _L =2.5 Ω, R _{gen} =3 Ω		13.2		ns
Turn-off fall time	t _f			3.5		ns
Body-diode reverse recovery time	t _{rr}	I _f =8A, dI/dt=100A/μs		22.9		ns
Body-diode reverse recovery charge	Q _{rr}	I _f =8A, dI/dt=100A/μs		18.3		nC

NOTE :

1. The value of R_{θja} is measured with the device mounted on 1in² FR-4 board of 2oz. Copper, in still air environment with T_a=25°C. The power dissipation P_{dsm} is based on R_{θja} max. allowed junction temperature of 150°C. The value in any given applications depends on the user's specific board design, and the max. temperature of 175°C may be used if the PCB allows it.
2. The power dissipation P_d is based on T_{j(max.)}=175°C, using junction-to-case thermal resistance, and is more useful setting the upper dissipation limit for cases where additional heatsinking is used.
3. The repetitive rating and the pulse width are limited by junction temperature T_{j(max.)}=175°C.
4. The R_{θja} is the sum of the thermal impedance from junction to case R_{θjc} and case to ambient.
5. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.
6. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{j(max.)}=175°C.
7. The maximum current rating is limited by bond-wires.
8. These tests are performed with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_a=25°C. The SOA curve provides a single pulse rating.

Complementary MOSFET

ELM24604HA-S

Typical Electrical and Thermal Characteristics (N-ch)

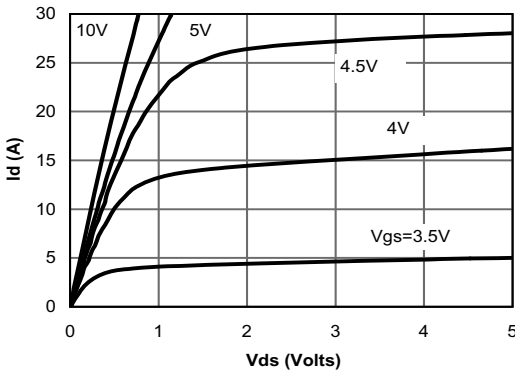


Figure 1: On-Region Characteristics

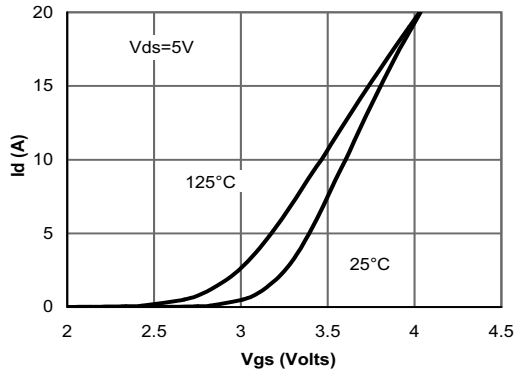


Figure 2: Transfer Characteristics

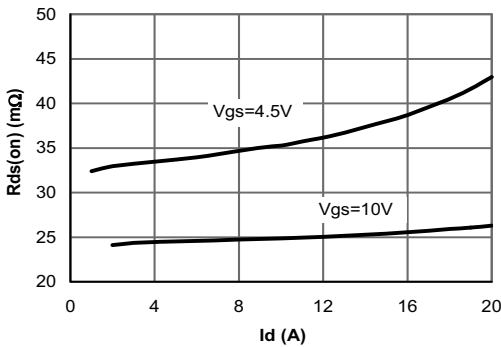


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

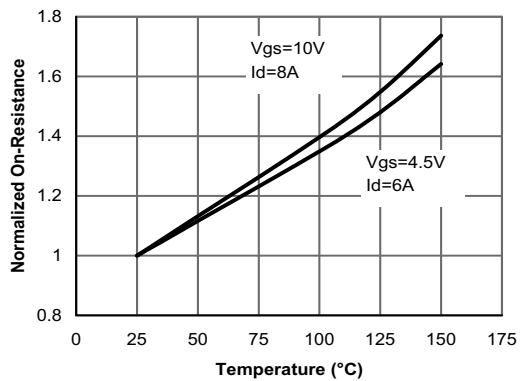


Figure 4: On-Resistance vs. Junction Temperature

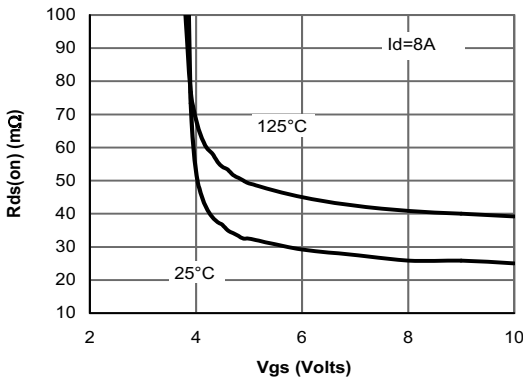


Figure 5: On-Resistance vs. Gate-Source Voltage

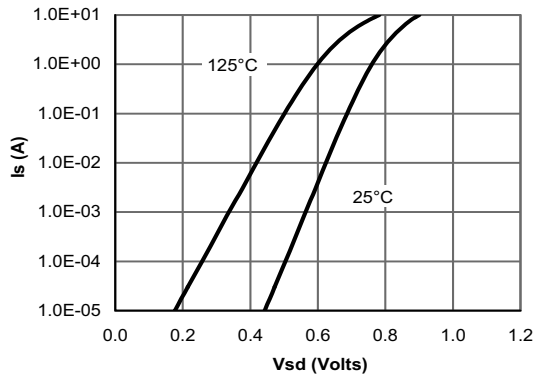


Figure 6: Body-Diode Characteristics

Complementary MOSFET

ELM24604HA-S

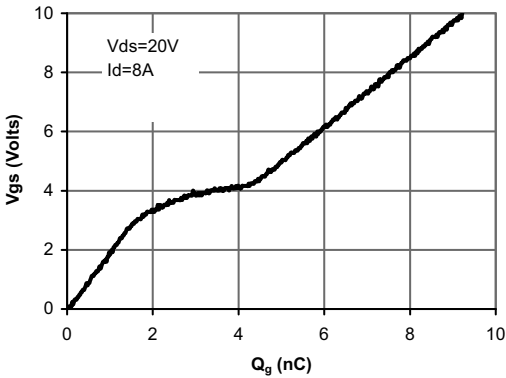


Figure 7: Gate-Charge Characteristics

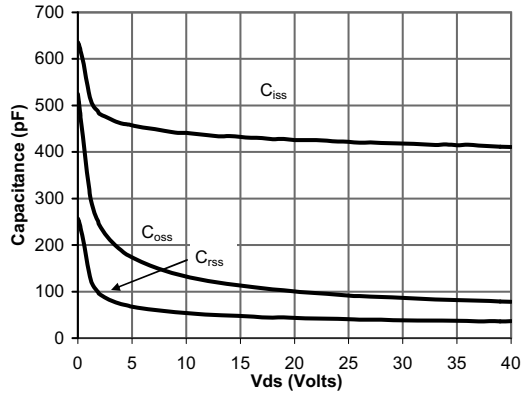


Figure 8: Capacitance Characteristics

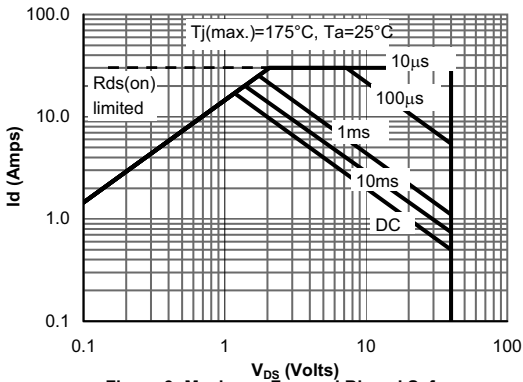


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

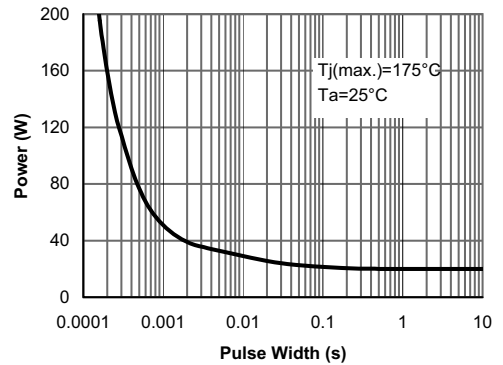


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

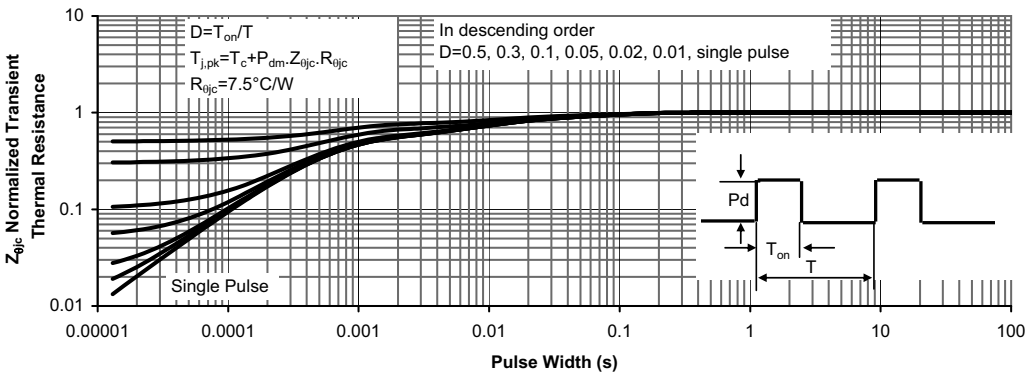


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Complementary MOSFET

ELM24604HA-S

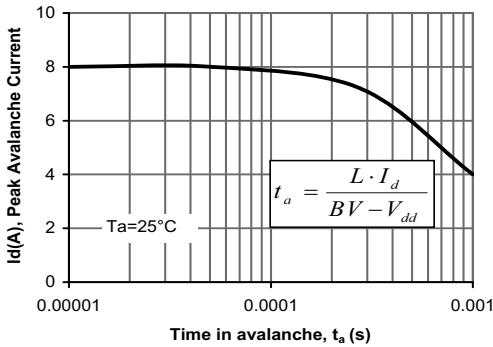


Figure 12: Single Pulse Avalanche capability

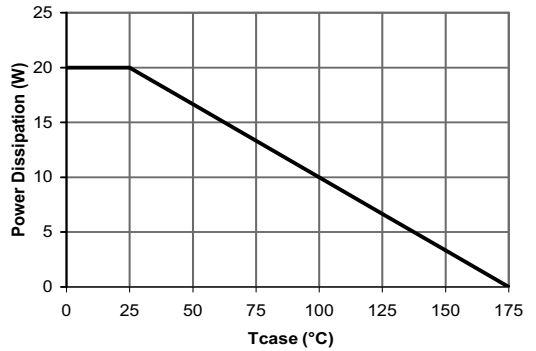


Figure 13: Power De-rating (Note B)

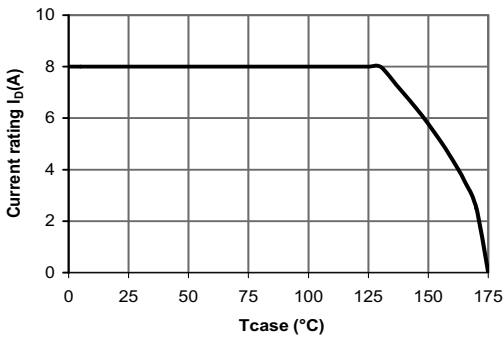


Figure 14: Current De-rating (Note B)

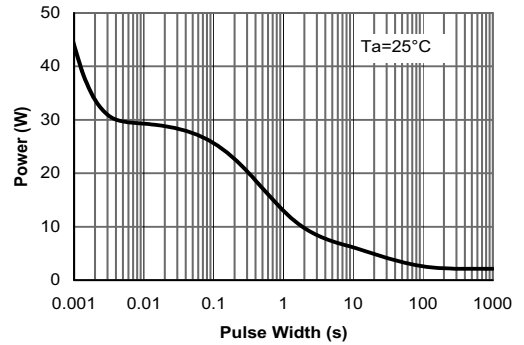


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

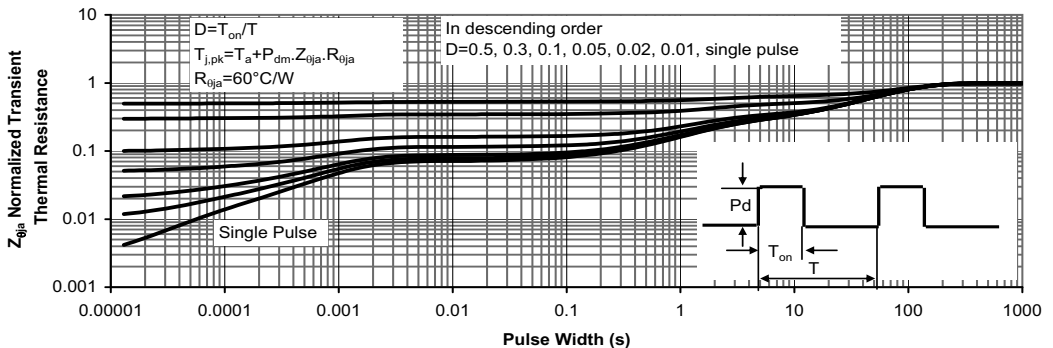


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

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ELM24604HA-S

■ Electrical Characteristics (P-ch)

T_a=25°C

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
STATIC PARAMETERS						
Drain-source breakdown voltage	BV _{dss}	I _d =-10mA, V _{gs} =0V	-40			V
Zero gate voltage drain current	I _{dss}	V _d =-32V V _{gs} =0V			-1	μA
		T _j =55°C			-5	
Gate-body leakage current	I _{gss}	V _d =0V, V _{gs} =±20V			±100	nA
Gate threshold voltage	V _{gs(th)}	V _d =V _{gs} , I _d =-250 μA	-1.0	-1.8	-3.0	V
On state drain current	I _{d(on)}	V _{gs} =-10V, V _d =-5V	-30			A
Static drain-source on-resistance	R _{ds(on)}	V _{gs} =-10V I _d =-8A		41	50	mΩ
		T _j =125°C		62		
		V _{gs} =-4.5V, I _d =-4A		57	70	mΩ
Forward transconductance	G _{fs}	V _d =-5V, I _d =-8A		16		S
Diode forward voltage	V _{sd}	I _s =-1A, V _{gs} =0V		-0.75	-1.00	V
Max. body-diode continuous current	I _s				-8	A
DYNAMIC PARAMETERS						
Input capacitance	C _{iss}	V _{gs} =0V, V _d =-20V, f=1MHz		657		pF
Output capacitance	C _{oss}			143		pF
Reverse transfer capacitance	C _{rss}			63		pF
Gate resistance	R _g	V _{gs} =0V, V _d =0V, f=1MHz		6.5		Ω
SWITCHING PARAMETERS						
Total gate charge (10V)	Q _g	V _{gs} =-10V, V _d =-20V		14.1		nC
Total gate charge (4.5V)	Q _g			7.0		nC
Gate-source charge	Q _{gs}	I _d =-8A		2.2		nC
Gate-drain charge	Q _{gd}			4.1		nC
Turn-on delay time	t _{d(on)}	V _{gs} =-10V, V _d =-20V R _L =2.5 Ω, R _{gen} =3 Ω		8.0		ns
Turn-on rise time	t _r			12.2		ns
Turn-off delay time	t _{d(off)}			24.0		ns
Turn-off fall time	t _f			12.5		ns
Body diode reverse recovery time	t _{rr}	I _f =-8A, dI/dt=100A/μs		23.2		ns
Body diode reverse recovery charge	Q _{rr}	I _f =-8A, dI/dt=100A/μs		18.2		nC

NOTE :

1. The value of R_{θja} is measured with the device mounted on 1in² FR-4 board of 2oz. Copper, in still air environment with T_a=25°C. The power dissipation P_{dsm} is based on R_{θja} max. allowed junction temperature of 150°C. The value in any given applications depends on the user's specific board design, and the max. temperature of 175°C may be used if the PCB allows it.
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7. The maximum current rating is limited by bond-wires.
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Typical Electrical and Thermal Characteristics (P-ch)

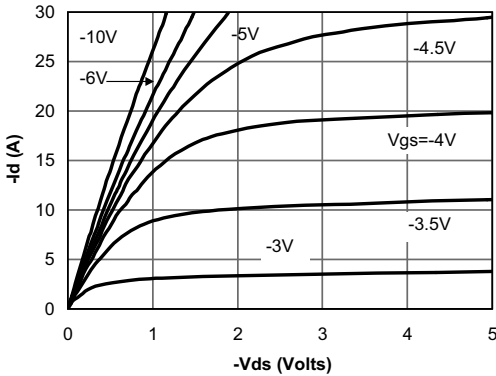


Fig 1: On-Region Characteristics

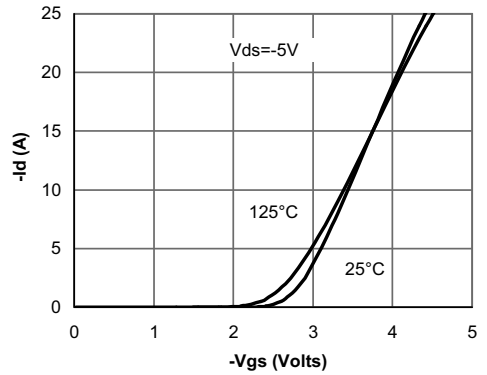


Figure 2: Transfer Characteristics

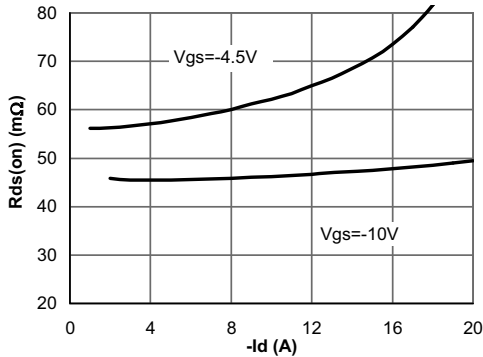


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

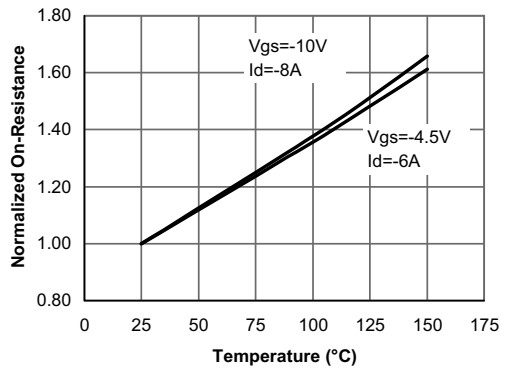


Figure 4: On-Resistance vs. Junction Temperature

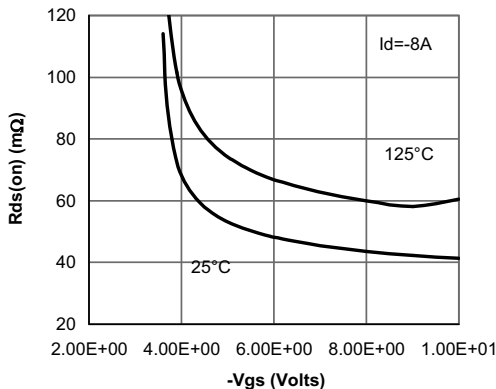


Figure 5: On-Resistance vs. Gate-Source Voltage

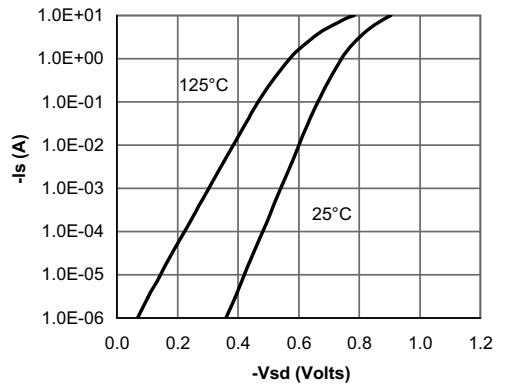
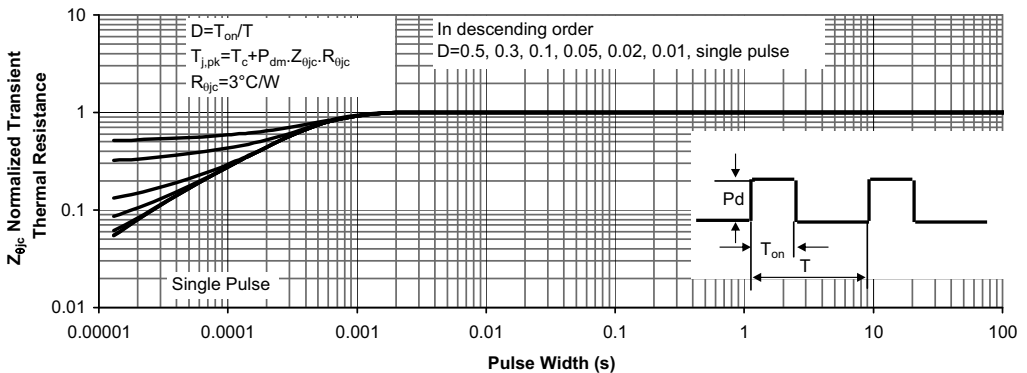
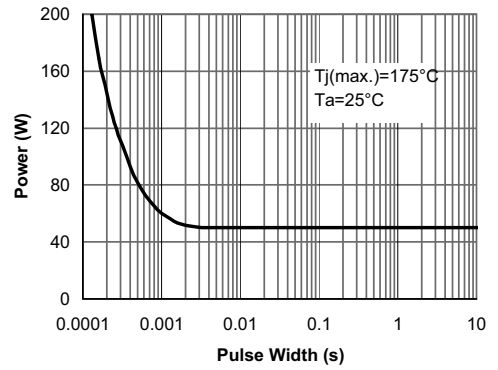
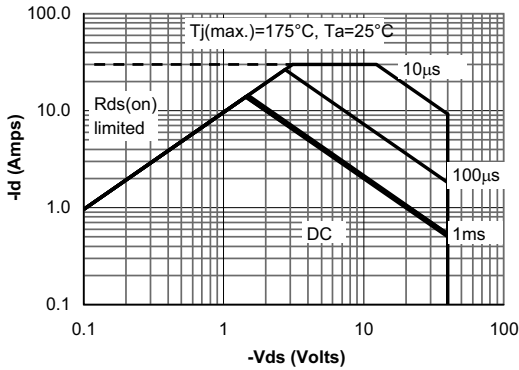
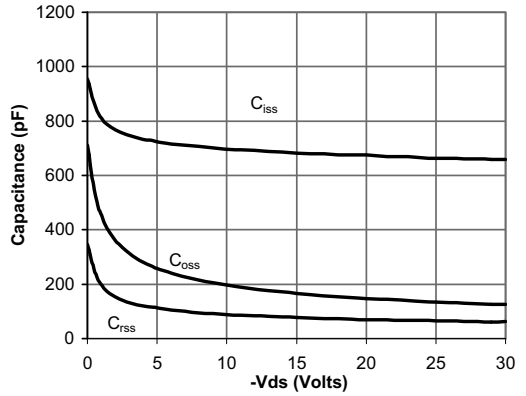
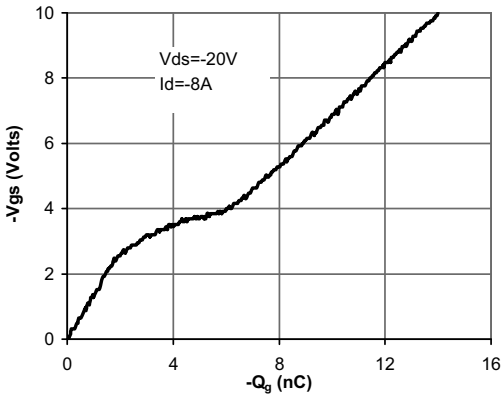


Figure 6: Body-Diode Characteristics

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ELM24604HA-S

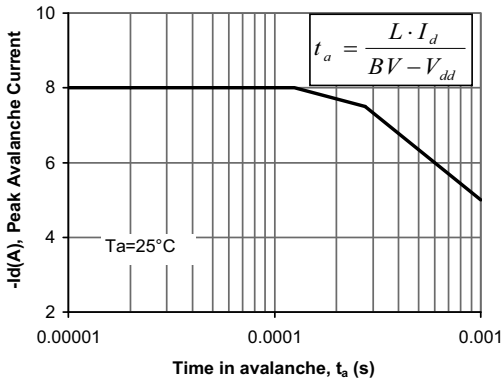


Figure 12: Single Pulse Avalanche capability

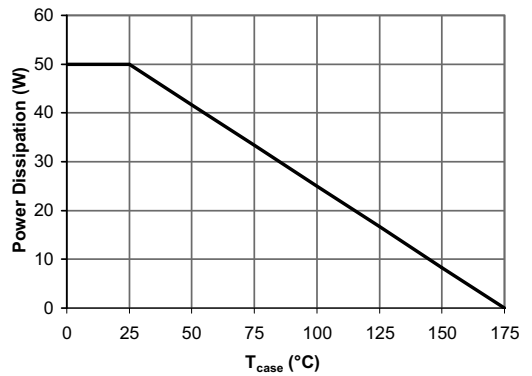


Figure 13: Power De-rating (Note B)

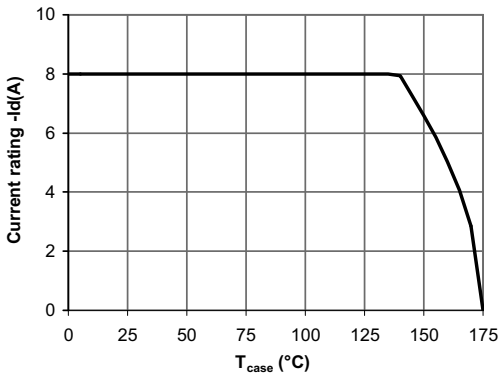


Figure 14: Current De-rating (Note B)

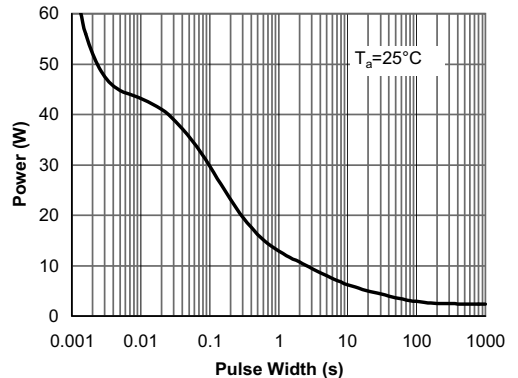


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

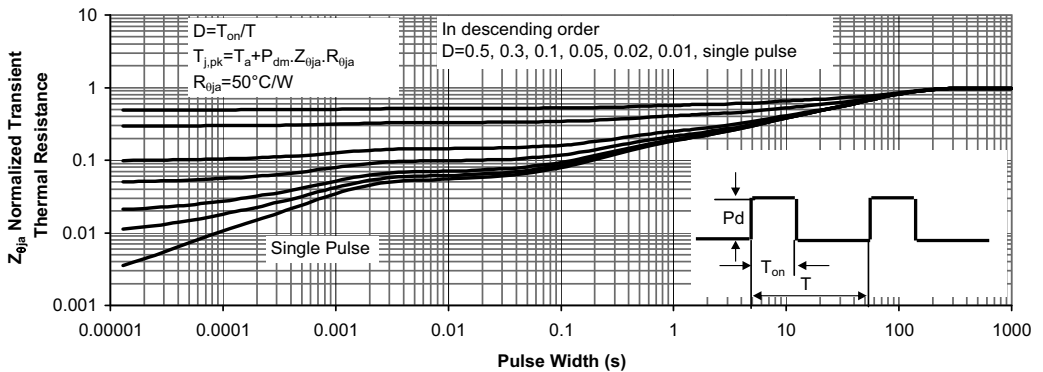


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)